

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,297	CHEN, PO-LUN
Examiner	Art Unit
Pichard H Kim	2871

	SEARCHED				
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Text Search (349/112)-see printout	7/7/2006	RHK		